Product Change Notification - LIAL-12DRIZ026

Date:
14 Nov 2018
Product Category:
8-bit Microcontrollers
Affected CPNs:

Notification subject:
CCB 3547.001 Final Notice: Qualification of MTAI as an additional final test site for selected Atmel ATTINY device family available in 8L SOIC package.
Notification text:

PCN Status:
Final notification

PCN Type:
Manufacturing Change

Microchip Parts Affected:
Please open one of the icons found in the Affected CPNs section above.

NOTE: For your convenience Microchip includes identical files in two formats (.pdf and .xls).

Description of Change:
Qualification of MTAI as an additional final test site for selected Atmel ATTINY device family available in 8L SOIC package

Pre Change:
Tested at LPI final test site or tested at MPHL final test site

Post Change:
Tested at LPI final test site or tested at MPHL final test site or tested at MTAI final test site.

Pre and Post Change Summary:

	Pre Change		Post Change		
Final Test Site	Lingsen Precision Industries, LTD. (LPI)	Microchip Technology Operations (Philippines) Corporation (MPHL)	Lingsen Precision Industries, LTD. (LPI)	Microchip Technology Operations (Philippines) Corporation (MPHL)	Microchip Technology Thailand (HQ)(MTAI)

Impacts to Data Sheet:
None

Change Impact:
None

Reason for Change:
To improve manufacturability by qualifying MTAI as an additional final test site.

Change Implementation Status:
In Progress

Estimated First Ship Date:
December 3, 2018 (date code: 1849)

NOTE: Please be advised that after the estimated first ship date customers may receive pre and post change parts

Time Table Summary:

	November 2018					December 2018				
Workweek	44	45	46	47	48	49	50	51	52	53
Final PCN Issue Date			X							
Qual Report Availability			X							
Estimated Implementation Date						X				

Method to Identify Change:
Traceability code

Qualification Report:
Please open the attachments included with this PCN labeled as PCN_#_Qual Report.

Revision History:
November 14, 2018: Issued final notification. Attached is the qualification report. Provided estimated first ship date to be on December 3, 2018.

The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable products.

Attachment(s):
PCN_LIAL-12DRIZ026_REPORT.pdf

Please contact your local Microchip sales office with questions or concerns regarding this notification.

Terms and Conditions:

If you wish to receive Microchip PCNs via email please register for our PCN email service at our PCN home page select register then fill in the required fields. You will find instructions about registering for Microchips PCN email service in the PCN FAQ section.
If you wish to change your PCN profile, including opt out, please go to the PCN home page select login and sign into your myMicrochip account. Select a profile option from the left navigation bar and make the applicable selections.

Affected Catalog Part Numbers (CPN)

ATTINY13-20SSU
ATTINY13-20SSUR
ATTINY13A-SSURA4

QUALIFICATION REPORT SUMMARY

PCN #: LIAL-12DRIZ026

Date
October 31, 2018

Qualification of MTAI as an additional final test site for selected Atmel ATTINY device family available in 8L SOIC package.

Purpose: **Qualification of MTAI as an additional final test site for selected Atmel ATTINY device family available in 8L SOIC package.**

CCB No.: **3547.001**

Test / Evaluation	Test Conditions / Parameters	Results
Datalog / Bin Comparison	• Compare test numbers, test names, test limit, test sequence, bin assignments & pass/fail results. • Accept if all match or justify the differences	Passed
Site by site verification	• Verifies the channel map has the correct site assignments and tester/handler communication work correctly	Passed
Correlation lot report	• Yield at each step and reject analysis between systems. 5K units are tested for each program conversion we perform. • Accept on yield match within 1%	Passed
Unit to unit parametric correlation	• A full assembly strip characterized on both systems and graphed vs each other & the data sheet limits	Passed
Test stability	• 50 loop test performed with no datalog delays • Accept on 0 fails	Passed
Parametric test stability verification	• Use Real Time Statistics software to create CPK report of all parametric tests • Accept on Cpk > 1.67 or explainable	Passed